

# \*RETURN TO FMF - LOCATION 7540

Re Edit

QUERY CONTROL FORM		RTIS USE ONLY	
Application No. <u>09/892,895</u>	Prepared by <u>KWW</u>	Tracking Number	
Examiner-GAU <u>DICUS — 1774</u>	Date <u>6-11-04</u>	Week Dat	
No. of queries			

## JACKET

- |                      |                        |                    |                      |
|----------------------|------------------------|--------------------|----------------------|
| a. Serial No.        | f. Foreign Priority    | k. Print Claim(s)  | <u>①</u> p. PTO-1449 |
| b. Applicant(s)      | g. Disclaimer          | l. Print Fig.      | q. PTOL-85b          |
| c. Continuing Data   | h. Microfiche Appendix | m. Searched Column | r. Abstract          |
| d. PCT               | i. Title               | n. PTO-270/328     | s. Sheets/Figs       |
| e. Domestic Priority | j. Claims Allowed      | o. PTO-892         | t. Other             |

## SPECIFICATION

- a. Page Missing
- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

## CLAIMS

- a. Claim(s) Missing
- b. Improper Dependency
- c. Duplicate Numbers
- d. Incorrect Numbering
- e. Index Disagrees
- f. Punctuation
- g. Amendments
- h. Bracketing
- i. Missing Text
- j. Duplicate Text
- k. Other

MESSAGE ① PTO-1449: IDS p. 3 of 3 dated

1-12-2004 - does not contain Examiner's initials -  
Signature. Please Supply.

Thanez initials KWW

RESPONSE

initials

**INFORMATION  
DISCLOSURE  
CITATION  
PTO-1449**

Atty. Docket No. 010845

Serial No. 09/892,895

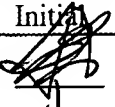


Applicant(s): HAYASHI, Hiromichi et al.

Filing Date: June 28, 2001

Group Art Unit: 1774

JAN 12 2004

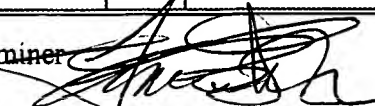
**U.S. PATENT DOCUMENTS**

Examiner Initial		Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
	AA	3,791,841	Carmellini et al.	02/12/74	117	3.4	
	AB	3,533,822	E.T. Bailey	10/13/70	117	3.4	
	AC	2,970,076	F.L. Porth	01/31/61			
_____	AD						
_____	AE						

**FOREIGN PATENT DOCUMENTS**

	Document No.	Date	Country	Translation (Yes or No)
_____	AF			
_____	AG			
_____	AH			
_____	AI			
_____	AJ			

**OTHER DOCUMENTS**

_____	AK	
_____	AL	
Examiner 	Date Considered	1/12/04